	P									
Form PTO 1449	13	U.S. DESARTMENT OF	FCOMMERCE	ATTY DOCKET NO. SERIAL NO.			10.			
Form PTO 1449 U.S. DEPARTMENT OF COMMERCE PATERY AND TRADEMARK OFFICE			249256US6X	•	10/785,063					
TOER				APPLICANT						
NOT OF I		ENCES CITED BY APP	LICANT					•		
LISTOFT	KEFER	ENCES CITED BY AFF	LICANI	Tomohisa HIGUCHI		·				
,				FILING DATE		GROUP				
				February 25, 2004		2186				
				U.S. PATENT DOCUMENTS		<u> </u>				
				U.S. PATENT DOCUMENTS			* * * * * * * * * * * * * * * * * * * *			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS		ING DATE PROPRIATE		
11	AA	6,424,029	7/23/2002	T. GIESLER						
-4-	AB			1	 		-4			
						 				
	AC				<u> </u>					
	AD							_		
	AE						_	•		
	-				 					
	AF				 	 				
	AG				 			·		
. Ī	AH				<u> </u>					
	Αl									
	AJ				1					
			······		 					
	AK				 	<u> </u>				
	AL									
	AM			·						
	AN									
<u> </u>						<u></u>	171			
			FC	REIGN PATENT DOCUMENTS	_			<u></u>		
		DOCUMENT			COUNTRY			TRANSLATION		
		NUMBER	DATE	COUNTRY		YE	S	NO		
	AO	WO 01/24108	04/05/2001	WIPO (with English Abstract)				· X		
	ΑP	0 557 934	09/01/1993	EUROPE		 		X		
	AQ							·		
<u> </u>		· · · · · · · · · · · · · · · · · · ·				†				
	AR	<u> </u>				 				
	AS .			110						
	AT							<u> </u>		
	AU									
· · · · · · · · · · · · · · · · · · ·	AV									
·		L	L	<u> </u>	-4.0-	- 1				
1				(Including Author, Title, Date, Pertine	nt Pages,	e(C.)				
1		Patent Abstracts of Jap	oan, JP 2003	-006578, January 10, 2003						
11 /	AW				9					
<u> </u>	-			:						
	AX]				•				
							•			
	AY									
	AT									
	†									
l	AZ					Additional References sheet(s) attached				
	<u></u>	44			to a citard					
Examiner		3/			Date Co	onsidered		115/06		
*Evaminar !	nitial if	reference is considered	whether or o	ot citation is in conformance with MPEP	609; Draw	line throug	n citation	if not in		
ıı "Examiner: li	ni ua l if i	reierence is considered,	wnemer or n	m with next communication to applicant.	,					